Group:Common preparations

Vampset: Adapted frequency off (50Hz)

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 15:51:49	Test End:	05-joulu-2014 15:52:06
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Group end:Common preparations

Group:265 Sn.xxxx personal preparations

Vampset: CT&VT settings + output matrix

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 15:52:40	Test End:	05-joulu-2014 15:55:33
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Group end:265 Sn.xxxx personal preparations

Hardware Configuration

Test Equipment

Type	Serial Number
CMC356	HE344P

Hardware Check

Performed At	Result	Details
5.12.2014 10:47:20	Passed	

Group:Overcurrent stage I> (50/51)

Group:Motor mode

Group:CT 5A

Test Object - Device Settings

Substation/Bay:

Substation:		Substation address:	
Bay:		Bay address:	

Device:

Name/description:	CT=5A Mot.Nom.=4A	Manufacturer:	
Device type:		Device address:	
Serial/model number:			
Additional info 1:			
Additional info 2:			

Vampset: Disable stages

Test State:

Command executed

Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 15:56:06	Test End:	05-joulu-2014 15:56:23
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Vampset: 50/51

Test State:

Command executed

Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 15:56:57	Test End:	05-joulu-2014 15:58:37
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Settings

General

No. of ramp states:	6
Total steps per test:	306
Total time per test:	32,400
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 1 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 1	360,0 mA 30,00 ° 50,000 Hz	360,0 mA 30,00 ° 50,000 Hz	440,0 mA 30,00 ° 50,000 Hz	7,600 A 30,00 ° 50,000 Hz	7,600 A 30,00 ° 50,000 Hz	8,400 A 30,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No

Sig 1 From	360,0 mA	360,0 mA	440,0 mA	7,600 A	7,600 A	8,400 A
Sig 1 To	360,0 mA	440,0 mA	320,0 mA	7,600 A	8,400 A	7,200 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	20,00 mA	-20,00 mA
Sig 1 d/dt	0,000 A/s	10,00 mA/s	-10,00 mA/s	0,000 A/s	200,0 mA/s	-200,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	81	121	1	41	61
Ramp Time	1,000s	8,100s	12,100s	1,000s	4,100s	6,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 15:59:14	Test End:	05-joulu-2014 15:59:23
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 1	400,0 mA	404,0 mA	10,00 mA	10,00 mA	4,000 mA	+	32,00
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 1	388,0 mA	390,0 mA	10,00 mA	10,00 mA	2,000 mA	+	11,90
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 1	8,000 A	8,020 A	200,0 mA	200,0 mA	20,00 mA	+	30,00
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 1	7,760 A	7,760 A	200,0 mA	200,0 mA	0,000 A	+	64,40

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	306
Total time per test:	32,400
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 2 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 2	360,0 mA -70,00 ° 50,000 Hz	360,0 mA -70,00 ° 50,000 Hz	440,0 mA -70,00 ° 50,000 Hz	7,600 A -70,00 ° 50,000 Hz	7,600 A -70,00 ° 50,000 Hz	8,400 A -70,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	360,0 mA	360,0 mA	440,0 mA	7,600 A	7,600 A	8,400 A
Sig 1 To	360,0 mA	440,0 mA	320,0 mA	7,600 A	8,400 A	7,200 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	20,00 mA	-20,00 mA
Sig 1 d/dt	0,000 A/s	10,00 mA/s	-10,00 mA/s	0,000 A/s	200,0 mA/s	-200,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms

Ramp Steps	1	81	121	1	41	61
Ramp Time	1,000s	8,100s	12,100s	1,000s	4,100s	6,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 15:59:59	Test End:	05-joulu-2014 16:00:08
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 2	400,0 mA	407,0 mA	10,00 mA	10,00 mA	7,000 mA	+	22,70
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 2	388,0 mA	391,0 mA	10,00 mA	10,00 mA	3,000 mA	+	63,60
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 2	8,000 A	8,020 A	200,0 mA	200,0 mA	20,00 mA	+	52,50
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 2	7,760 A	7,760 A	200,0 mA	200,0 mA	0,000 A	+	51,00

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	306
Total time per test:	32,400
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 3 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 3	360,0 mA -150,00 ° 50,000 Hz	360,0 mA -150,00 ° 50,000 Hz	440,0 mA -150,00 ° 50,000 Hz	7,600 A -150,00 ° 50,000 Hz	7,600 A -150,00 ° 50,000 Hz	8,400 A -150,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	360,0 mA	360,0 mA	440,0 mA	7,600 A	7,600 A	8,400 A
Sig 1 To	360,0 mA	440,0 mA	320,0 mA	7,600 A	8,400 A	7,200 A
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA	0,000 A	20,00 mA	-20,00 mA
Sig 1 d/dt	0,000 A/s	10,00 mA/s	-10,00 mA/s	0,000 A/s	200,0 mA/s	-200,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	81	121	1	41	61
Ramp Time	1,000s	8,100s	12,100s	1,000s	4,100s	6,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No

Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:00:45	Test End:	05-joulu-2014 16:00:54
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	400,0 mA	404,0 mA	10,00 mA	10,00 mA	4,000 mA	+	40,60
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 3	388,0 mA	389,0 mA	10,00 mA	10,00 mA	1,000 mA	+	25,30
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 3	8,000 A	8,020 A	200,0 mA	200,0 mA	20,00 mA	+	49,00
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 3	7,760 A	7,760 A	200,0 mA	200,0 mA	0,000 A	+	55,00

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Test Settings

General

No. of ramp states:	3
Total steps per test:	283
Total time per test:	29,200
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 1 / Magnitude
I 1(+) / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3
I 1	200,0 mA 30,00 ° 50,000 Hz	200,0 mA 30,00 ° 50,000 Hz	360,0 mA 30,00 ° 50,000 Hz
I 1(+)	240,0 mA 30,00 ° 100,00 Hz	240,0 mA 30,00 ° 100,00 Hz	240,0 mA 30,00 ° 100,00 Hz
Force abs. Phases	Yes	Yes	Yes
Sig 1 From	200,0 mA	200,0 mA	360,0 mA
Sig 1 To	200,0 mA	360,0 mA	240,0 mA
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA
Sig 1 d/dt	0,000 A/s	10,00 mA/s	-10,00 mA/s
Sig 2 From	240,0 mA	240,0 mA	240,0 mA
Sig 2 To	240,0 mA	240,0 mA	240,0 mA
Sig 2 Delta	0,000 A	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s	0,000 A/s
DI1	0	0	0
dt per Step	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	161	121
Ramp Time	1,000s	16,100s	12,100s
Trigger	None	Bin	Bin
Trigger Logic		OR	OR
Start (A1)		1	0

Step back	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:01:30	Test End:	05-joulu-2014 16:01:42
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 1	320,0 mA	319,0 mA	10,00 mA	10,00 mA	-1,000 mA	+	7,900
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 1	310,4 mA	304,0 mA	10,00 mA	10,00 mA	-6,400 mA	+	42,40

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Test Settings

General

No. of ramp states:	3
Total steps per test:	283
Total time per test:	29,200
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 2 / Magnitude
I 2(+) / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3
I 2	200,0 mA -70,00 ° 50,000 Hz	200,0 mA -70,00 ° 50,000 Hz	360,0 mA -70,00 ° 50,000 Hz
I 2(+)	240,0 mA -70,00 ° 100,00 Hz	240,0 mA -70,00 ° 100,00 Hz	240,0 mA -70,00 ° 100,00 Hz
Force abs. Phases	Yes	Yes	Yes
Sig 1 From	200,0 mA	200,0 mA	360,0 mA
Sig 1 To	200,0 mA	360,0 mA	240,0 mA
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA
Sig 1 d/dt	0,000 A/s	10,00 mA/s	-10,00 mA/s
Sig 2 From	240,0 mA	240,0 mA	240,0 mA
Sig 2 To	240,0 mA	240,0 mA	240,0 mA
Sig 2 Delta	0,000 A	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s	0,000 A/s
DI1	0	0	0
dt per Step	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	161	121
Ramp Time	1,000s	16,100s	12,100s
Trigger	None	Bin	Bin
Trigger Logic		OR	OR
Start (A1)		1	0
Step back	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:02:18	Test End:	05-joulu-2014 16:02:30
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 2	320,0 mA	323,0 mA	10,00 mA	10,00 mA	3,000 mA	+	25,70
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 2	310,4 mA	307,0 mA	10,00 mA	10,00 mA	-3,400 mA	+	23,10

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states:	3
Total steps per test:	283
Total time per test:	29,200
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 3 / Magnitude
I 3(+) / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3
I 3	200,0 mA -150,00 ° 50,000 Hz	200,0 mA -150,00 ° 50,000 Hz	360,0 mA -150,00 ° 50,000 Hz
I 3(+)	240,0 mA -150,00 ° 100,00 Hz	240,0 mA -150,00 ° 100,00 Hz	240,0 mA -150,00 ° 100,00 Hz
Force abs. Phases	Yes	Yes	Yes
Sig 1 From	200,0 mA	200,0 mA	360,0 mA
Sig 1 To	200,0 mA	360,0 mA	240,0 mA
Sig 1 Delta	0,000 A	1,000 mA	-1,000 mA
Sig 1 d/dt	0,000 A/s	10,00 mA/s	-10,00 mA/s
Sig 2 From	240,0 mA	240,0 mA	240,0 mA
Sig 2 To	240,0 mA	240,0 mA	240,0 mA
Sig 2 Delta	0,000 A	0,000 A	0,000 A
Sig 2 d/dt	0,000 A/s	0,000 A/s	0,000 A/s
DI1	0	0	0
dt per Step	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	161	121
Ramp Time	1,000s	16,100s	12,100s
Trigger	None	Bin	Bin
Trigger Logic		OR	OR
Start (A1)		1	0
Step back	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:03:07	Test End:	05-joulu-2014 16:03:18
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	320,0 mA	317,0 mA	10,00 mA	10,00 mA	-3,000 mA	+	45,30
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 3	310,4 mA	302,0 mA	10,00 mA	10,00 mA	-8,400 mA	+	37,90

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Operation time (DT) min. 40ms and 1.0s:

Test Settings

State	Normal situtation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I 1	200,0 mA -10,00 ° 50,000 Hz	414,0 mA -10,00 ° 50,000 Hz	376,0 mA -10,00 ° 50,000 Hz	376,0 mA -10,00 ° 50,000 Hz	8,280 A -10,00 ° 50,000 Hz	7,520 A -10,00 ° 50,000 Hz	7,520 A -10,00 ° 50,000 Hz	376,0 mA -10,00 ° 50,000 Hz
I 2	200,0 mA -130,00 ° 50,000 Hz	414,0 mA -130,00 ° 50,000 Hz	376,0 mA -130,00 ° 50,000 Hz	376,0 mA -130,00 ° 50,000 Hz	376,0 mA -130,00 ° 50,000 Hz	376,0 mA -130,00 ° 50,000 Hz	376,0 mA -130,00 ° 50,000 Hz	376,0 mA -130,00 ° 50,000 Hz
I 3	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	8,280 A 110,00 ° 50,000 Hz	7,520 A 110,00 ° 50,000 Hz	7,520 A 110,00 ° 50,000 Hz	376,0 mA 110,00 ° 50,000 Hz

State	Cold boot #2	No trip after boot (Grp2)
I 1	376,0 mA -10,00 ° 50,000 Hz	7,520 A -10,00 ° 50,000 Hz
I 2	376,0 mA -130,00 ° 50,000 Hz	7,520 A -130,00 ° 50,000 Hz
I 3	376,0 mA 110,00 ° 50,000 Hz	7,520 A 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:03:55	Test End:	05-joulu-2014 16:04:16
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	52,40 ms	22,40 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	56,20 ms	16,20 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	47,70 ms	-47,30 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	46,40 ms	-48,60 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	48,30 ms	18,30 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	23,00 ms	23,00 ms	1,012 s	11,80 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	47,90 ms	-47,10 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	46,70 ms	-48,30 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms	0,000 s	1,023 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	**No trip after boot (Grp2)**						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Group end:CT 5A

Group end:Motor mode

Group end:Overcurrent stage I> (50/51)

Group:Overcurrent stage I'> (50/51)

Group:Motor mode

Group:CT 5A

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:

Substation address:
Bay address:

Device:

Name/description: CT=5A Mot.Nom.=4A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:

Manufacturer:
Device address:

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:04:50	Test End:	05-joulu-2014 16:05:11
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Vampset: 50/51

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:05:44	Test End:	05-joulu-2014 16:05:58
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Settings

General

No. of ramp states: 6
Total steps per test: 186
Total time per test: 20,400
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I'1 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'1	360,0 mA 30,00 ° 50,000 Hz	360,0 mA 30,00 ° 50,000 Hz	440,0 mA 30,00 ° 50,000 Hz	7,600 A 30,00 ° 50,000 Hz	7,600 A 30,00 ° 50,000 Hz	8,400 A 30,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	360,0 mA	360,0 mA	440,0 mA	7,600 A	7,600 A	8,400 A
Sig 1 To	360,0 mA	440,0 mA	320,0 mA	7,600 A	8,400 A	7,200 A
Sig 1 Delta	0,000 A	2,000 mA	-2,000 mA	0,000 A	25,00 mA	-25,00 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	250,0 mA/s	-250,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	41	61	1	33	49
Ramp Time	1,000s	4,100s	6,100s	1,000s	3,300s	4,900s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR

Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
Version: 3.00 SR 2
Test Start: 05-joulu-2014 16:06:34
Test End: 05-joulu-2014 16:06:40
User Name: Jesse Saastamoinen
Manager:
Company: Schneider Electric - Vamp

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'1	400,0 mA	404,0 mA	10,00 mA	10,00 mA	4,000 mA	+	55,20
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'1	388,0 mA	390,0 mA	10,00 mA	10,00 mA	2,000 mA	+	49,60
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'1	8,000 A	8,025 A	200,0 mA	200,0 mA	25,00 mA	+	45,70
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'1	7,760 A	7,750 A	200,0 mA	200,0 mA	-10,00 mA	+	64,20

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states: 6
Total steps per test: 186
Total time per test: 20,400
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I'2 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'2	360,0 mA -70,00 ° 50,000 Hz	360,0 mA -70,00 ° 50,000 Hz	440,0 mA -70,00 ° 50,000 Hz	7,600 A -70,00 ° 50,000 Hz	7,600 A -70,00 ° 50,000 Hz	8,400 A -70,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	360,0 mA	360,0 mA	440,0 mA	7,600 A	7,600 A	8,400 A
Sig 1 To	360,0 mA	440,0 mA	320,0 mA	7,600 A	8,400 A	7,200 A
Sig 1 Delta	0,000 A	2,000 mA	-2,000 mA	0,000 A	25,00 mA	-25,00 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	250,0 mA/s	-250,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	41	61	1	33	49
Ramp Time	1,000s	4,100s	6,100s	1,000s	3,300s	4,900s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
Version: 3.00 SR 2

Test Start:	05-joulu-2014 16:07:16	Test End:	05-joulu-2014 16:07:21
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'2	400,0 mA	402,0 mA	10,00 mA	10,00 mA	2,000 mA	+	72,40
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'2	388,0 mA	390,0 mA	10,00 mA	10,00 mA	2,000 mA	+	61,00
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'2	8,000 A	8,000 A	200,0 mA	200,0 mA	0,000 A	+	58,90
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'2	7,760 A	7,750 A	200,0 mA	200,0 mA	-10,00 mA	+	54,00

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	186
Total time per test:	20,400
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I'3 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'3	360,0 mA -150,00 ° 50,000 Hz	360,0 mA -150,00 ° 50,000 Hz	440,0 mA -150,00 ° 50,000 Hz	7,600 A -150,00 ° 50,000 Hz	7,600 A -150,00 ° 50,000 Hz	8,400 A -150,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	360,0 mA	360,0 mA	440,0 mA	7,600 A	7,600 A	8,400 A
Sig 1 To	360,0 mA	440,0 mA	320,0 mA	7,600 A	8,400 A	7,200 A
Sig 1 Delta	0,000 A	2,000 mA	-2,000 mA	0,000 A	25,00 mA	-25,00 mA
Sig 1 d/dt	0,000 A/s	20,00 mA/s	-20,00 mA/s	0,000 A/s	250,0 mA/s	-250,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	41	61	1	33	49
Ramp Time	1,000s	4,100s	6,100s	1,000s	3,300s	4,900s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:07:58	Test End:	05-joulu-2014 16:08:03
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'3	400,0 mA	404,0 mA	10,00 mA	10,00 mA	4,000 mA	+	43,70
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'3	388,0 mA	390,0 mA	10,00 mA	10,00 mA	2,000 mA	+	46,40
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'3	8,000 A	8,000 A	200,0 mA	200,0 mA	0,000 A	+	53,80
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'3	7,760 A	7,750 A	200,0 mA	200,0 mA	-10,00 mA	+	53,90

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Operation time (DT) min. 80ms and 1.0s:

Test Settings

State	Normal situtation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I'1	200,0 mA -10,00 ° 50,000 Hz	415,0 mA -10,00 ° 50,000 Hz	380,0 mA -10,00 ° 50,000 Hz	380,0 mA -10,00 ° 50,000 Hz	8,280 A -10,00 ° 50,000 Hz	7,520 A -10,00 ° 50,000 Hz	7,520 A -10,00 ° 50,000 Hz	380,0 mA -10,00 ° 50,000 Hz
I'2	200,0 mA -130,00 ° 50,000 Hz	415,0 mA -130,00 ° 50,000 Hz	380,0 mA -130,00 ° 50,000 Hz	380,0 mA -130,00 ° 50,000 Hz	380,0 mA -130,00 ° 50,000 Hz	380,0 mA -130,00 ° 50,000 Hz	380,0 mA -130,00 ° 50,000 Hz	380,0 mA -130,00 ° 50,000 Hz
I'3	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	8,280 A 110,00 ° 50,000 Hz	7,520 A 110,00 ° 50,000 Hz	7,520 A 110,00 ° 50,000 Hz	380,0 mA 110,00 ° 50,000 Hz

State	Cold boot #2	No trip after boot (Grp2)
I'1	380,0 mA -10,00 ° 50,000 Hz	7,520 A -10,00 ° 50,000 Hz
I'2	380,0 mA -130,00 ° 50,000 Hz	7,520 A -130,00 ° 50,000 Hz
I'3	380,0 mA 110,00 ° 50,000 Hz	7,520 A 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:08:40	Test End:	05-joulu-2014 16:09:00
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	60,00 ms	60,00 ms	20,00 ms	65,50 ms	5,500 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	80,00 ms	28,00 ms	28,00 ms	88,90 ms	8,900 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	67,60 ms	-27,40 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	66,40 ms	-28,60 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	60,00 ms	60,00 ms	20,00 ms	48,80 ms	-11,20 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	1,000 s	28,00 ms	28,00 ms	992,2 ms	-7,800 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	67,60 ms	-27,40 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	66,30 ms	-28,70 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	108,0 ms	95,00 ms	0,000 s	1,028 s	95,00 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	**No trip after boot (Grp2)**						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Group end:CT 5A

Group end:Motor mode

Group end:Overcurrent stage I'> (50/51)

Group:Overcurrent stage I>> (50/51)

Group:Motor mode

Group:CT 5A

Test Object - Device Settings

Substation/Bay:

Substation:		Substation address:	
Bay:		Bay address:	

Device:

Name/description:	CT=5A Mot.Nom.=4A	Manufacturer:	
Device type:		Device address:	
Serial/model number:			
Additional info 1:			
Additional info 2:			

Vampset: Disable stages

Test State:

Command executed

Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:09:35	Test End:	05-joulu-2014 16:09:55
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Vampset: 50/51

Test State:

Command executed

Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:10:29	Test End:	05-joulu-2014 16:12:08
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Operation time (DT) min. 40ms:

Test Settings

State	Normal situtation	Pick-up Grp1	Drop-off Grp1
I 1	200,0 mA -10,00 ° 50,000 Hz	415,0 mA -10,00 ° 50,000 Hz	375,0 mA -10,00 ° 50,000 Hz
I 2	200,0 mA -130,00 ° 50,000 Hz	415,0 mA -130,00 ° 50,000 Hz	375,0 mA -130,00 ° 50,000 Hz
I 3	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:12:45	Test End:	05-joulu-2014 16:12:45
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	37,50 ms	7,500 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	41,20 ms	1,200 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	47,70 ms	-47,30 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	46,60 ms	-48,40 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up Grp1	Drop-off Grp1
Assess	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms
Start (A1)	0	1	0
Trip (T1)	0	1	0

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Group end:CT 5A

Group end:Motor mode

Group end:Overcurrent stage I>> (50/51)

Group:Overcurrent stage I>>> (50/51)

Group:Motor mode

Group:CT 5A

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:
Substation address:
Bay address:

Device:

Name/description: CT=5A Mot.Nom.=4A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:
Manufacturer:
Device address:

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 05-joulu-2014 16:13:19
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp
Version: 3.00 SR 2
Test End: 05-joulu-2014 16:13:35
Manager:

ampset: 50/51

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:14:09	Test End:	05-joulu-2014 16:15:49
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Operation time (DT) min. 30ms:

Test Settings

State	Normal situtation	Pick-up 1 Grp1	Drop-off 1 Grp1	Normal situtation	Pick-up 2 Grp1	Drop-off 2 Grp1
I 1	200,0 mA -10,00 ° 50,000 Hz	414,4 mA -10,00 ° 50,000 Hz	376,0 mA -10,00 ° 50,000 Hz	200,0 mA -10,00 ° 50,000 Hz	600,0 mA -10,00 ° 50,000 Hz	376,0 mA -10,00 ° 50,000 Hz
I 2	200,0 mA -130,00 ° 50,000 Hz	414,4 mA -130,00 ° 50,000 Hz	376,0 mA -130,00 ° 50,000 Hz	200,0 mA -130,00 ° 50,000 Hz	600,0 mA -130,00 ° 50,000 Hz	376,0 mA -130,00 ° 50,000 Hz
I 3	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:16:25	Test End:	05-joulu-2014 16:16:26
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start 1 pick-up Grp1	Pick-up 1 Grp1	Pick-up 1 Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	20,00 ms	38,80 ms	8,800 ms	+
Start 2 pick-up Grp1	Pick-up 2 Grp1	Pick-up 2 Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	0,000 s	21,80 ms	-8,200 ms	+
Trip 1 pick-up Grp1	Pick-up 1 Grp1	Pick-up 1 Grp1	Trip (T1) 0>1	50,00 ms	50,00 ms	0,000 s	42,90 ms	-7,100 ms	+
Trip 2 pick-up Grp1	Pick-up 2 Grp1	Pick-up 2 Grp1	Trip (T1) 0>1	30,00 ms	30,00 ms	0,000 s	25,60 ms	-4,400 ms	+
Start 1 drop-off Grp1	Drop-off 1 Grp1	Drop-off 1 Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	47,60 ms	-47,40 ms	+
Start 2 drop-off Grp1	Drop-off 2 Grp1	Drop-off 2 Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	54,30 ms	-40,70 ms	+
Trip 1 drop-off Grp1	Drop-off 1 Grp1	Drop-off 1 Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	46,60 ms	-48,40 ms	+
Trip 2 drop-off Grp1	Drop-off 2 Grp1	Drop-off 2 Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	53,30 ms	-41,70 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up 1 Grp1	Drop-off 1 Grp1	Normal situtation	Pick-up 2 Grp1	Drop-off 2 Grp1
Assess	+	+	+	+	+	+
Tolerance	0,000 s	50,00 ms	95,00 ms	0,000 s	50,00 ms	95,00 ms
Start (A1)	0	1	0	0	1	0
Trip (T1)	0	1	0	0	1	0

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

---------- Group end:CT 5A ----------

---------- Group end:Motor mode ----------

---------- Group end:Overcurrent stage I>>> (50/51) ----------
---------- Group:Overcurrent stage I'>> (50/51) ----------
---------- Group:Motor mode ----------
---------- Group:CT 5A ----------

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:
Substation address:
Bay address:

Device:

Name/description: CT=5A Mot.Nom.=4A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:
Manufacturer:
Device address:

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 05-joulu-2014 16:17:00
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp
Version: 3.00 SR 2
Test End: 05-joulu-2014 16:17:16
Manager:

Vampset: 50/51

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 05-joulu-2014 16:17:50
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp
Version: 3.00 SR 2
Test End: 05-joulu-2014 16:18:02
Manager:

Operation time (DT) min. 40ms:

Test Settings

State	Normal situtation	Pick-up Grp1	Drop-off Grp1
I'1	200,0 mA -10,00 ° 50,000 Hz	415,0 mA -10,00 ° 50,000 Hz	375,0 mA -10,00 ° 50,000 Hz
I'2	200,0 mA -130,00 ° 50,000 Hz	415,0 mA -130,00 ° 50,000 Hz	375,0 mA -130,00 ° 50,000 Hz
I'3	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz	200,0 mA 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:18:39	Test End:	05-joulu-2014 16:18:39
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	30,00 ms	30,00 ms	30,00 ms	46,00 ms	16,00 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	40,00 ms	23,00 ms	23,00 ms	49,70 ms	9,700 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	95,00 ms	95,00 ms	0,000 s	47,90 ms	-47,10 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	95,00 ms	95,00 ms	0,000 s	46,70 ms	-48,30 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up Grp1	Drop-off Grp1
Assess	+	+	+
Tolerance	0,000 s	63,00 ms	95,00 ms
Start (A1)	0	1	0
Trip (T1)	0	1	0

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Group end:CT 5A

Group end:Motor mode

Group end:Overcurrent stage I'>> (50/51)

Group:Thermal overload stage T> (49)

Group:Motor mode

Group:CT 5A

Test Object - Device Settings

Substation/Bay:

Substation:		Substation address:	
Bay:		Bay address:	

Device:

Name/description:	CT=5A Mot.Nom.=4A	Manufacturer:	
Device type:		Device address:	
Serial/model number:			
Additional info 1:			
Additional info 2:			

Vampset: Disable stages

Test State:

Command executed

Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:19:13	Test End:	05-joulu-2014 16:19:30
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Vampset: 49

Test State:

Command executed

Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:20:03	Test End:	05-joulu-2014 16:21:48
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Mcc=0.10xIn,A=60%,Tau=2min,Cool=1.0xTau:

Test Settings

State	Pick-up	Steady	Drop-off	Cold boot #1	No trip after boot
I 1	1,200 A -10,00 ° 50,000 Hz	400,0 mA -10,00 ° 50,000 Hz	0,000 A -10,00 ° 50,000 Hz	0,000 A -10,00 ° 50,000 Hz	0,000 A -10,00 ° 50,000 Hz
I 2	1,200 A -130,00 ° 50,000 Hz	400,0 mA -130,00 ° 50,000 Hz	0,000 A -130,00 ° 50,000 Hz	0,000 A -130,00 ° 50,000 Hz	0,000 A -130,00 ° 50,000 Hz
I 3	1,200 A 110,00 ° 50,000 Hz	400,0 mA 110,00 ° 50,000 Hz	0,000 A 110,00 ° 50,000 Hz	0,000 A 110,00 ° 50,000 Hz	0,000 A 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:22:25	Test End:	05-joulu-2014 16:26:54
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up	Pick-up	Start (A1) 0>1	8,279 s	800,0 ms	800,0 ms	8,422 s	143,2 ms	+
Trip pick-up Grp1	Pick-up	Pick-up	Trip (T1) 0>1	14,13 s	800,0 ms	800,0 ms	14,42 s	282,4 ms	+
Start drop-off Grp1	Steady	Drop-off	Start (A1) 1>0	67,45 s	3,200 s	3,200 s	68,98 s	1,530 s	+
Trip drop-off Grp1	Steady	Drop-off	Trip (T1) 1>0	6,155 s	2,800 s	2,800 s	7,485 s	1,330 s	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Pick-up	Steady	Drop-off	Cold boot #1	No trip after boot
Assess	+	+	+	+	+
Tolerance	15,03 s	0,000 s	74,56 s	0,000 s	0,000 s
Start (A1)	1	1	0	0	X
Trip (T1)	1	1	0	0	0

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:27:28	Test End:	05-joulu-2014 16:27:49
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Vampset: 49

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:28:23	Test End:	05-joulu-2014 16:30:08

User Name: Jesse Saastamoinen Manager:
Company: Schneider Electric - Vamp

Mcc=1.20xIn,A=99%,Tau=180min,Cool=1.0xTau:

Test Settings

State	Pick-up	Drop-off
I 1	12,00 A -10,00 ° 50,000 Hz	0,000 A -10,00 ° 50,000 Hz
I 2	12,00 A -130,00 ° 50,000 Hz	0,000 A -130,00 ° 50,000 Hz
I 3	12,00 A 110,00 ° 50,000 Hz	0,000 A 110,00 ° 50,000 Hz

Test Module

Name: OMICRON State Sequencer Version: 3.00 SR 2
Test Start: 05-joulu-2014 16:30:44 Test End: 05-joulu-2014 16:40:41
User Name: Jesse Saastamoinen Manager:
Company: Schneider Electric - Vamp

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up	Pick-up	Start (A1) 0>1	21,54 s	6,000 s	6,000 s	26,32 s	4,782 s	+
Trip pick-up Grp1	Pick-up	Pick-up	Trip (T1) 0>1	42,09 s	6,000 s	6,000 s	46,81 s	4,722 s	+
Trip drop-off Grp1	Drop-off	Drop-off	Trip (T1) 1>0	554,0 s	24,93 s	24,93 s	554,9 s	982,3 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Pick-up	Drop-off
Assess	+	+
Tolerance	48,09 s	578,9 s
Start (A1)	1	X
Trip (T1)	1	0

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Group end:CT 5A

Group end:Motor mode

Group end:Thermal overload stage T> (49)

Group:Unbalance stage I2> (46)

Group:Motor mode
Group:CT 5A

Test Object - Device Settings

Substation/Bay:

Substation:		Substation address:	
Bay:		Bay address:	

Device:

Name/description:	CT=5A Mot.Nom.=4A	Manufacturer:	
Device type:		Device address:	
Serial/model number:			
Additional info 1:			
Additional info 2:			

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:41:16	Test End:	05-joulu-2014 16:41:32
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Vampset: 46

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:42:06	Test End:	05-joulu-2014 16:43:46
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Settings

General

No. of ramp states:	6
Total steps per test:	182
Total time per test:	20,000
No. of test executions:	1

Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 1 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 1	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	3,600 A 30,00 ° 50,000 Hz	8,800 A 30,00 ° 50,000 Hz	8,800 A 30,00 ° 50,000 Hz	10,00 A 30,00 ° 50,000 Hz
I 2	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz
I 3	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	4,000 A	4,000 A	3,600 A	8,800 A	8,800 A	10,00 A
Sig 1 To	4,000 A	3,600 A	4,000 A	8,800 A	10,00 A	8,800 A
Sig 1 Delta	0,000 A	-10,00 mA	10,00 mA	0,000 A	25,00 mA	-25,00 mA
Sig 1 d/dt	0,000 A/s	-100,0 mA/s	100,0 mA/s	0,000 A/s	250,0 mA/s	-250,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	41	41	1	49	49
Ramp Time	1,000s	4,100s	4,100s	1,000s	4,900s	4,900s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:44:22	Test End:	05-joulu-2014 16:44:30
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 1	3,760 A	3,740 A	120,0 mA	120,0 mA	-20,00 mA	+	89,60
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 1	3,772 A	3,810 A	120,0 mA	120,0 mA	38,00 mA	+	35,90
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 1	9,572 A	9,600 A	120,0 mA	120,0 mA	28,00 mA	+	34,80
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 1	9,152 A	9,075 A	120,0 mA	120,0 mA	-77,00 mA	+	97,90

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	182
Total time per test:	20,000
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 2 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 1	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	1,600 A 30,00 ° 50,000 Hz	1,600 A 30,00 ° 50,000 Hz	1,600 A 30,00 ° 50,000 Hz
I 2	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	3,600 A -90,00 ° 50,000 Hz	8,800 A -90,00 ° 50,000 Hz	8,800 A -90,00 ° 50,000 Hz	10,00 A -90,00 ° 50,000 Hz
I 3	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	4,000 A	4,000 A	3,600 A	8,800 A	8,800 A	10,00 A
Sig 1 To	4,000 A	3,600 A	4,000 A	8,800 A	10,00 A	8,800 A
Sig 1 Delta	0,000 A	-10,00 mA	10,00 mA	0,000 A	25,00 mA	-25,00 mA
Sig 1 d/dt	0,000 A/s	-100,0 mA/s	100,0 mA/s	0,000 A/s	250,0 mA/s	-250,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	41	41	1	49	49
Ramp Time	1,000s	4,100s	4,100s	1,000s	4,900s	4,900s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:45:07	Test End:	05-joulu-2014 16:45:15
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 2	3,760 A	3,750 A	120,0 mA	120,0 mA	-10,00 mA	+	65,50
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 2	3,772 A	3,810 A	120,0 mA	120,0 mA	38,00 mA	+	61,80
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 2	9,572 A	9,600 A	120,0 mA	120,0 mA	28,00 mA	+	82,90
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 2	9,152 A	9,050 A	120,0 mA	120,0 mA	-102,0 mA	+	28,60

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	182
Total time per test:	20,000
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 3 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 1	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	800,0 mA 30,00 ° 50,000 Hz	800,0 mA 30,00 ° 50,000 Hz	800,0 mA 30,00 ° 50,000 Hz
I 2	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz
I 3	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	3,600 A 150,00 ° 50,000 Hz	8,800 A 150,00 ° 50,000 Hz	8,800 A 150,00 ° 50,000 Hz	10,00 A 150,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	4,000 A	4,000 A	3,600 A	8,800 A	8,800 A	10,00 A
Sig 1 To	4,000 A	3,600 A	4,000 A	8,800 A	10,00 A	8,800 A
Sig 1 Delta	0,000 A	-10,00 mA	10,00 mA	0,000 A	25,00 mA	-25,00 mA
Sig 1 d/dt	0,000 A/s	-100,0 mA/s	100,0 mA/s	0,000 A/s	250,0 mA/s	-250,0 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	41	41	1	49	49
Ramp Time	1,000s	4,100s	4,100s	1,000s	4,900s	4,900s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:45:52	Test End:	05-joulu-2014 16:46:01
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	3,760 A	3,740 A	120,0 mA	120,0 mA	-20,00 mA	+	18,00
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 3	3,772 A	3,810 A	120,0 mA	120,0 mA	38,00 mA	+	48,10
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 3	9,572 A	9,625 A	120,0 mA	120,0 mA	53,00 mA	+	32,50
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 3	9,152 A	9,050 A	120,0 mA	120,0 mA	-102,0 mA	+	1,100

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states: 6
Total steps per test: 366
Total time per test: 28,300
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I 1 / Phase

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 1	4,000 A 0,00 ° 50,000 Hz	4,000 A 0,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 170,00 ° 50,000 Hz
I 2	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz
I 3	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	0,00 °	0,00 °	-10,00 °	130,00 °	130,00 °	170,00 °
Sig 1 To	0,00 °	-10,00 °	0,00 °	130,00 °	170,00 °	130,00 °
Sig 1 Delta	0,00 °	-0,10 °	0,10 °	0,00 °	0,50 °	-0,50 °
Sig 1 d/dt	0 °/s	-2 °/s	2 °/s	0 °/s	5 °/s	-5 °/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	101	101	1	81	81
Ramp Time	1,000s	5,050s	5,050s	1,000s	8,100s	8,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
Version: 3.00 SR 2
Test Start: 05-joulu-2014 16:46:37
Test End: 05-joulu-2014 16:46:51
User Name: Jesse Saastamoinen
Manager:
Company: Schneider Electric - Vamp

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 1	-3,44 °	-3,80 °	1,72 °	1,72 °	-0,36 °	+	48,70
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 1	-3,27 °	-2,50 °	1,72 °	1,72 °	0,77 °	+	4,900
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 1	161,00 °	162,50 °	6,80 °	9,50 °	1,50 °	+	79,50
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 1	141,50 °	140,00 °	4,20 °	4,60 °	-1,50 °	+	39,40

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	366
Total time per test:	28,300
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I 2 / Phase

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 1	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz
I 2	4,000 A 0,00 ° 50,000 Hz	4,000 A 0,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 170,00 ° 50,000 Hz
I 3	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	0,00 °	0,00 °	-10,00 °	130,00 °	130,00 °	170,00 °
Sig 1 To	0,00 °	-10,00 °	0,00 °	130,00 °	170,00 °	130,00 °
Sig 1 Delta	0,00 °	-0,10 °	0,10 °	0,00 °	0,50 °	-0,50 °
Sig 1 d/dt	0 °/s	-2 °/s	2 °/s	0 °/s	5 °/s	-5 °/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	101	101	1	81	81
Ramp Time	1,000s	5,050s	5,050s	1,000s	8,100s	8,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:47:27	Test End:	05-joulu-2014 16:47:40
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 2	-3,44 °	-3,80 °	1,72 °	1,72 °	-0,36 °	+	19,30
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 2	-3,27 °	-2,40 °	1,72 °	1,72 °	0,87 °	+	31,60
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 2	161,00 °	162,00 °	6,80 °	9,50 °	1,00 °	+	83,30
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 2	141,50 °	140,00 °	4,20 °	4,60 °	-1,50 °	+	26,60

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Test Settings

General

No. of ramp states: 6
Total steps per test: 366
Total time per test: 28,300
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I 3 / Phase

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 1	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz
I 2	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz
I 3	4,000 A 0,00 ° 50,000 Hz	4,000 A 0,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 170,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	0,00 °	0,00 °	-10,00 °	130,00 °	130,00 °	170,00 °
Sig 1 To	0,00 °	-10,00 °	0,00 °	130,00 °	170,00 °	130,00 °
Sig 1 Delta	0,00 °	-0,10 °	0,10 °	0,00 °	0,50 °	-0,50 °
Sig 1 d/dt	0 °/s	-2 °/s	2 °/s	0 °/s	5 °/s	-5 °/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	101	101	1	81	81
Ramp Time	1,000s	5,050s	5,050s	1,000s	8,100s	8,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
Version: 3.00 SR 2
Test Start: 05-joulu-2014 16:48:17
Test End: 05-joulu-2014 16:48:30
User Name: Jesse Saastamoinen
Manager:
Company: Schneider Electric - Vamp

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I 3	-3,44 °	-3,90 °	1,72 °	1,72 °	-0,46 °	+	20,50
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I 3	-3,27 °	-2,50 °	1,72 °	1,72 °	0,77 °	+	30,00
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I 3	161,00 °	162,00 °	6,80 °	9,50 °	1,00 °	+	59,70
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I 3	141,50 °	139,50 °	4,20 °	4,60 °	-2,00 °	+	29,40

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Operation time (DT) min. 1s and 5s:

Test Settings

State	Normal situtation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I 1	2,000 A -10,00 ° 50,000 Hz	2,000 A -10,00 ° 50,000 Hz	2,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	10,00 A -10,00 ° 50,000 Hz	7,920 A -10,00 ° 50,000 Hz	7,920 A -10,00 ° 50,000 Hz	200,0 mA -10,00 ° 50,000 Hz
I 2	2,000 A -130,00 ° 50,000 Hz	2,400 A -130,00 ° 50,000 Hz	2,100 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz	1,600 A -130,00 ° 50,000 Hz	1,600 A -130,00 ° 50,000 Hz	1,600 A -130,00 ° 50,000 Hz	200,0 mA -130,00 ° 50,000 Hz
I 3	2,000 A 110,00 ° 50,000 Hz	2,000 A 110,00 ° 50,000 Hz	2,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	800,0 mA 110,00 ° 50,000 Hz	800,0 mA 110,00 ° 50,000 Hz	800,0 mA 110,00 ° 50,000 Hz	205,0 mA 110,00 ° 50,000 Hz

State	Cold boot #2	No trip after boot (Grp2)
I 1	200,0 mA -10,00 ° 50,000 Hz	7,920 A -10,00 ° 50,000 Hz
I 2	200,0 mA -130,00 ° 50,000 Hz	1,600 A -130,00 ° 50,000 Hz
I 3	205,0 mA 110,00 ° 50,000 Hz	800,0 mA 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:49:08	Test End:	05-joulu-2014 16:49:34
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	200,0 ms	200,0 ms	100,0 ms	126,2 ms	-73,80 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	1,000 s	175,0 ms	175,0 ms	929,6 ms	-70,40 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	450,0 ms	450,0 ms	0,000 s	407,3 ms	-42,70 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	450,0 ms	450,0 ms	0,000 s	406,3 ms	-43,70 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	200,0 ms	200,0 ms	100,0 ms	189,0 ms	-11,00 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	5,000 s	225,0 ms	225,0 ms	4,992 s	-7,800 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	450,0 ms	450,0 ms	0,000 s	407,2 ms	-42,80 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	450,0 ms	450,0 ms	0,000 s	406,3 ms	-43,70 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	1,175 s	450,0 ms	0,000 s	5,175 s	450,0 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	**No trip after boot (Grp2)**						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:50:08	Test End:	05-joulu-2014 16:50:28
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Vampset: 46

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:51:02	Test End:	05-joulu-2014 16:52:42
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Operation time (INV) min. K=1 and (max.) K=50:

Test Settings

State	Normal situtation	Pick-up Grp1 (I2=2.1%)	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2
I 1	4,000 A -10,00 ° 50,000 Hz	8,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz
I 2	4,000 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz	12,00 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz

I 3	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:53:19	Test End:	05-joulu-2014 16:55:21
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1 (I2=2.1%)	Pick-up Grp1 (I2=2.1%)	Start (A1) 0>1	200,0 ms	200,0 ms	100,0 ms	113,8 ms	-86,20 ms	+
Trip pick-up Grp1	Pick-up Grp1 (I2=2.1%)	Pick-up Grp1 (I2=2.1%)	Trip (T1) 0>1	9,032 s	406,0 ms	406,0 ms	8,917 s	-115,3 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	450,0 ms	450,0 ms	0,000 s	407,4 ms	-42,60 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	450,0 ms	450,0 ms	0,000 s	406,6 ms	-43,40 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	200,0 ms	200,0 ms	100,0 ms	189,0 ms	-11,00 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	115,1 s	5,175 s	5,175 s	115,0 s	-107,6 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	450,0 ms	450,0 ms	0,000 s	407,2 ms	-42,80 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	450,0 ms	450,0 ms	0,000 s	406,6 ms	-43,40 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up Grp1 (I2=2.1%)	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2
Assess	+	+	+	+	+	+
Tolerance	0,000 s	9,438 s	450,0 ms	0,000 s	120,3 s	450,0 ms
Start (A1)	0	1	0	0	1	0
Trip (T1)	0	1	0	0	1	0

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Group end:CT 5A

Group end:Motor mode

Test Object - Device Settings

Substation/Bay:

Substation:
Bay:
Substation address:
Bay address:

Device:

Name/description: CT=5A Mot.Nom.=4A
Device type:
Serial/model number:
Additional info 1:
Additional info 2:
Manufacturer:
Device address:

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 05-joulu-2014 16:55:55
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp
Version: 3.00 SR 2
Test End: 05-joulu-2014 16:56:11
Manager:

Vampset: 46

Test State:
Command executed
Test passed

Test Module

Name: OMICRON ExeCute
Test Start: 05-joulu-2014 16:56:45
User Name: Jesse Saastamoinen
Company: Schneider Electric - Vamp
Version: 3.00 SR 2
Test End: 05-joulu-2014 16:56:58
Manager:

Test Settings

General

No. of ramp states: 6
Total steps per test: 1340
Total time per test: 135,800
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I'1 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'1	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	3,600 A 30,00 ° 50,000 Hz	8,800 A 30,00 ° 50,000 Hz	8,800 A 30,00 ° 50,000 Hz	10,00 A 30,00 ° 50,000 Hz
I'2	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz

I'3	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	4,000 A	4,000 A	3,600 A	8,800 A	8,800 A	10,00 A
Sig 1 To	4,000 A	3,600 A	4,000 A	8,800 A	10,00 A	8,800 A
Sig 1 Delta	0,000 A	-2,400 mA	2,400 mA	0,000 A	2,400 mA	-2,400 mA
Sig 1 d/dt	0,000 A/s	-24,00 mA/s	24,00 mA/s	0,000 A/s	24,00 mA/s	-24,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	168	168	1	501	501
Ramp Time	1,000s	16,800s	16,800s	1,000s	50,100s	50,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:57:34	Test End:	05-joulu-2014 16:58:36
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'1	3,760 A	3,755 A	120,0 mA	120,0 mA	-4,800 mA	+	200,0
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'1	3,772 A	3,785 A	120,0 mA	120,0 mA	12,80 mA	+	20,30
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'1	9,572 A	9,580 A	120,0 mA	120,0 mA	8,000 mA	+	53,10
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'1	9,152 A	9,146 A	120,0 mA	120,0 mA	-6,400 mA	+	18,40

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	1340
Total time per test:	135,800
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I'2 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'1	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	1,600 A 30,00 ° 50,000 Hz	1,600 A 30,00 ° 50,000 Hz	1,600 A 30,00 ° 50,000 Hz
I'2	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	3,600 A -90,00 ° 50,000 Hz	8,800 A -90,00 ° 50,000 Hz	8,800 A -90,00 ° 50,000 Hz	10,00 A -90,00 ° 50,000 Hz

I'3	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz	800,0 mA 150,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	4,000 A	4,000 A	3,600 A	8,800 A	8,800 A	10,00 A
Sig 1 To	4,000 A	3,600 A	4,000 A	8,800 A	10,00 A	8,800 A
Sig 1 Delta	0,000 A	-2,400 mA	2,400 mA	0,000 A	2,400 mA	-2,400 mA
Sig 1 d/dt	0,000 A/s	-24,00 mA/s	24,00 mA/s	0,000 A/s	24,00 mA/s	-24,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	168	168	1	501	501
Ramp Time	1,000s	16,800s	16,800s	1,000s	50,100s	50,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 16:59:13	Test End:	05-joulu-2014 17:00:14
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'2	3,760 A	3,755 A	120,0 mA	120,0 mA	-4,800 mA	+	30,50
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'2	3,772 A	3,775 A	120,0 mA	120,0 mA	3,200 mA	+	43,00
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'2	9,572 A	9,575 A	120,0 mA	120,0 mA	3,200 mA	+	36,40
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'2	9,152 A	9,136 A	120,0 mA	120,0 mA	-16,00 mA	+	17,60

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	1340
Total time per test:	135,800
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I'3 / Magnitude

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'1	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	800,0 mA 30,00 ° 50,000 Hz	800,0 mA 30,00 ° 50,000 Hz	800,0 mA 30,00 ° 50,000 Hz
I'2	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	4,000 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz	1,600 A -90,00 ° 50,000 Hz

I'3	4,000 A 150,00 ° 50,000 Hz	4,000 A 150,00 ° 50,000 Hz	3,600 A 150,00 ° 50,000 Hz	8,800 A 150,00 ° 50,000 Hz	8,800 A 150,00 ° 50,000 Hz	10,00 A 150,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	4,000 A	4,000 A	3,600 A	8,800 A	8,800 A	10,00 A
Sig 1 To	4,000 A	3,600 A	4,000 A	8,800 A	10,00 A	8,800 A
Sig 1 Delta	0,000 A	-2,400 mA	2,400 mA	0,000 A	2,400 mA	-2,400 mA
Sig 1 d/dt	0,000 A/s	-24,00 mA/s	24,00 mA/s	0,000 A/s	24,00 mA/s	-24,00 mA/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	100,0 ms	100,0 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	168	168	1	501	501
Ramp Time	1,000s	16,800s	16,800s	1,000s	50,100s	50,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:00:51	Test End:	05-joulu-2014 17:01:52
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'3	3,760 A	3,753 A	120,0 mA	120,0 mA	-7,200 mA	+	7,200
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'3	3,772 A	3,780 A	120,0 mA	120,0 mA	8,000 mA	+	24,90
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'3	9,572 A	9,568 A	120,0 mA	120,0 mA	-4,000 mA	+	44,30
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'3	9,152 A	9,136 A	120,0 mA	120,0 mA	-16,00 mA	+	30,40

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Test Settings

General

No. of ramp states:	6
Total steps per test:	366
Total time per test:	28,300
No. of test executions:	1
Input Mode:	Direct
Fault Type:	

Ramped Quantities

I'1 / Phase

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I 1	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz	4,000 A 30,00 ° 50,000 Hz
I 2	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz
I 3	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz
I'1	4,000 A 0,00 ° 50,000 Hz	4,000 A 0,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 170,00 ° 50,000 Hz
I'2	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz
I'3	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	0,00 °	0,00 °	-10,00 °	130,00 °	130,00 °	170,00 °
Sig 1 To	0,00 °	-10,00 °	0,00 °	130,00 °	170,00 °	130,00 °
Sig 1 Delta	0,00 °	-0,10 °	0,10 °	0,00 °	0,50 °	-0,50 °
Sig 1 d/dt	0 °/s	-2 °/s	2 °/s	0 °/s	5 °/s	-5 °/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	101	101	1	81	81
Ramp Time	1,000s	5,050s	5,050s	1,000s	8,100s	8,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name:	OMICRON Ramping	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:02:28	Test End:	05-joulu-2014 17:02:42
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'1	-3,44 °	-3,80 °	1,72 °	1,72 °	-0,36 °	+	22,10
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'1	-3,27 °	-2,60 °	1,72 °	1,72 °	0,67 °	+	1,600
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'1	161,00 °	161,50 °	6,80 °	9,50 °	0,50 °	+	55,70
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'1	141,50 °	140,00 °	4,20 °	4,60 °	-1,50 °	+	93,90

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

Test Settings

General

No. of ramp states: 6
Total steps per test: 366
Total time per test: 28,300
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I'2 / Phase

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'1	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz
I'2	4,000 A 0,00 ° 50,000 Hz	4,000 A 0,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 170,00 ° 50,000 Hz
I'3	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	0,00 °	0,00 °	-10,00 °	130,00 °	130,00 °	170,00 °
Sig 1 To	0,00 °	-10,00 °	0,00 °	130,00 °	170,00 °	130,00 °
Sig 1 Delta	0,00 °	-0,10 °	0,10 °	0,00 °	0,50 °	-0,50 °
Sig 1 d/dt	0 °/s	-2 °/s	2 °/s	0 °/s	5 °/s	-5 °/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	101	101	1	81	81
Ramp Time	1,000s	5,050s	5,050s	1,000s	8,100s	8,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
Version: 3.00 SR 2
Test Start: 05-joulu-2014 17:03:18
Test End: 05-joulu-2014 17:03:32
User Name: Jesse Saastamoinen
Manager:
Company: Schneider Electric - Vamp

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'2	-3,44 °	-3,80 °	1,72 °	1,72 °	-0,36 °	+	34,60
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'2	-3,27 °	-2,60 °	1,72 °	1,72 °	0,67 °	+	37,80
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'2	161,00 °	162,00 °	6,80 °	9,50 °	1,00 °	+	69,70
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'2	141,50 °	139,50 °	4,20 °	4,60 °	-2,00 °	+	3,100

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Test Settings

General

No. of ramp states: 6
Total steps per test: 366
Total time per test: 28,300
No. of test executions: 1

Input Mode: Direct
Fault Type:

Ramped Quantities

I'3 / Phase

Ramp States

Ramp	Ramp 1	Ramp 2	Ramp 3	Ramp 4	Ramp 5	Ramp 6
I'1	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -120,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz	4,000 A -110,00 ° 50,000 Hz
I'2	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz	4,000 A 120,00 ° 50,000 Hz
I'3	4,000 A 0,00 ° 50,000 Hz	4,000 A 0,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 130,00 ° 50,000 Hz	4,000 A 170,00 ° 50,000 Hz
Force abs. Phases	Yes	No	No	No	No	No
Sig 1 From	0,00 °	0,00 °	-10,00 °	130,00 °	130,00 °	170,00 °
Sig 1 To	0,00 °	-10,00 °	0,00 °	130,00 °	170,00 °	130,00 °
Sig 1 Delta	0,00 °	-0,10 °	0,10 °	0,00 °	0,50 °	-0,50 °
Sig 1 d/dt	0 °/s	-2 °/s	2 °/s	0 °/s	5 °/s	-5 °/s
DI1	0	0	0	1	1	1
dt per Step	1,000 s	50,00 ms	50,00 ms	1,000 s	100,0 ms	100,0 ms
Ramp Steps	1	101	101	1	81	81
Ramp Time	1,000s	5,050s	5,050s	1,000s	8,100s	8,100s
Trigger	None	Bin	Bin	None	Bin	Bin
Trigger Logic		OR	OR		OR	OR
Start (A1)		1	0		1	0
Step back	No	No	No	No	No	No
Delay Time	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s	0,000 s

Test Module

Name: OMICRON Ramping
Version: 3.00 SR 2
Test Start: 05-joulu-2014 17:04:08
Test End: 05-joulu-2014 17:04:21
User Name: Jesse Saastamoinen
Manager:
Company: Schneider Electric - Vamp

Test Results

Assessment Results

Name/ Exec.	Ramp	Condition	Sig	Nom.	Act.	Tol.-	Tol.+	Dev.	Assess	Tact
Pick-up (Grp1)	Ramp 2	Start (A1) 0->1	I'3	-3,44 °	-3,70 °	1,72 °	1,72 °	-0,26 °	+	33,70
Drop-off (Grp1)	Ramp 3	Start (A1) 1->0	I'3	-3,27 °	-2,40 °	1,72 °	1,72 °	0,87 °	+	300,0
Pick-up (Grp2)	Ramp 5	Start (A1) 0->1	I'3	161,00 °	161,50 °	6,80 °	9,50 °	0,50 °	+	68,60
Drop-off (Grp2)	Ramp 6	Start (A1) 1->0	I'3	141,50 °	139,50 °	4,20 °	4,60 °	-2,00 °	+	23,00

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Operation time (DT) min. 1s and 5s:

Test Settings

State	Normal situtation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
I'1	2,000 A -10,00 ° 50,000 Hz	2,000 A -10,00 ° 50,000 Hz	2,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	10,00 A -10,00 ° 50,000 Hz	7,920 A -10,00 ° 50,000 Hz	7,920 A -10,00 ° 50,000 Hz	2,000 A -10,00 ° 50,000 Hz
I'2	2,000 A -130,00 ° 50,000 Hz	2,400 A -130,00 ° 50,000 Hz	2,100 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz	1,600 A -130,00 ° 50,000 Hz	1,600 A -130,00 ° 50,000 Hz	1,600 A -130,00 ° 50,000 Hz	2,000 A -130,00 ° 50,000 Hz
I'3	2,000 A 110,00 ° 50,000 Hz	2,000 A 110,00 ° 50,000 Hz	2,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	800,0 mA 110,00 ° 50,000 Hz	800,0 mA 110,00 ° 50,000 Hz	800,0 mA 110,00 ° 50,000 Hz	2,100 A 110,00 ° 50,000 Hz

State	Cold boot #2	No trip after boot (Grp2)
I'1	2,000 A -10,00 ° 50,000 Hz	7,920 A -10,00 ° 50,000 Hz
I'2	2,000 A -130,00 ° 50,000 Hz	1,600 A -130,00 ° 50,000 Hz
I'3	2,100 A 110,00 ° 50,000 Hz	800,0 mA 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:04:58	Test End:	05-joulu-2014 17:05:24
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Start (A1) 0>1	200,0 ms	200,0 ms	100,0 ms	164,6 ms	-35,40 ms	+
Trip pick-up Grp1	Pick-up Grp1	Pick-up Grp1	Trip (T1) 0>1	1,000 s	175,0 ms	175,0 ms	968,0 ms	-32,00 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	450,0 ms	450,0 ms	0,000 s	407,3 ms	-42,70 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	450,0 ms	450,0 ms	0,000 s	406,5 ms	-43,50 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	200,0 ms	200,0 ms	100,0 ms	189,0 ms	-11,00 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	5,000 s	225,0 ms	225,0 ms	4,992 s	-7,900 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	450,0 ms	450,0 ms	0,000 s	407,3 ms	-42,70 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	450,0 ms	450,0 ms	0,000 s	406,5 ms	-43,50 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up Grp1	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2	Cold boot #1	No trip after boot (Grp1)
Assess	+	+	+	+	+	+	+	+
Tolerance	0,000 s	1,175 s	450,0 ms	0,000 s	5,175 s	450,0 ms	0,000 s	0,000 s
Start (A1)	0	1	0	0	1	0	0	0
Trip (T1)	0	1	0	0	1	0	0	0
	Cold boot #2	**No trip after boot (Grp2)**						
Assess	+	+						
Tolerance	0,000 s	0,000 s						
Start (A1)	0	0						
Trip (T1)	0	0						

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:
Test passed

Vampset: Disable stages

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:05:58	Test End:	05-joulu-2014 17:06:19
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Vampset: 46

Test State:
Command executed
Test passed

Test Module

Name:	OMICRON ExeCute	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:06:52	Test End:	05-joulu-2014 17:07:05
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Operation time (INV) min. K=1 and (max.) K=50:

Test Settings

State	Normal situtation	Pick-up Grp1 (I2=2.1%)	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2
I'1	4,000 A -10,00 ° 50,000 Hz	8,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz	4,000 A -10,00 ° 50,000 Hz
I'2	4,000 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz	12,00 A -130,00 ° 50,000 Hz	4,000 A -130,00 ° 50,000 Hz
I'3	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz	4,000 A 110,00 ° 50,000 Hz

Test Module

Name:	OMICRON State Sequencer	Version:	3.00 SR 2
Test Start:	05-joulu-2014 17:07:42	Test End:	05-joulu-2014 17:09:44
User Name:	Jesse Saastamoinen	Manager:	
Company:	Schneider Electric - Vamp		

Test Results

Time Assessment

Name	Ignore before	Start	Stop	Tnom	Tdev-	Tdev+	Tact	Tdev	Assess
Start pick-up Grp1	Pick-up Grp1 (I2=2.1%)	Pick-up Grp1 (I2=2.1%)	Start (A1) 0>1	200,0 ms	200,0 ms	100,0 ms	177,0 ms	-23,00 ms	+
Trip pick-up Grp1	Pick-up Grp1 (I2=2.1%)	Pick-up Grp1 (I2=2.1%)	Trip (T1) 0>1	9,032 s	406,0 ms	406,0 ms	8,980 s	-52,40 ms	+
Start drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Start (A1) 1>0	450,0 ms	450,0 ms	0,000 s	407,4 ms	-42,60 ms	+
Trip drop-off Grp1	Drop-off Grp1	Drop-off Grp1	Trip (T1) 1>0	450,0 ms	450,0 ms	0,000 s	406,6 ms	-43,40 ms	+
Start pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Start (A1) 0>1	200,0 ms	200,0 ms	100,0 ms	189,2 ms	-10,80 ms	+
Trip pick-up Grp2	Pick-up Grp2	Pick-up Grp2	Trip (T1) 0>1	115,1 s	5,175 s	5,175 s	114,8 s	-307,6 ms	+
Start drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Start (A1) 1>0	450,0 ms	450,0 ms	0,000 s	407,2 ms	-42,80 ms	+
Trip drop-off Grp2	Drop-off Grp2	Drop-off Grp2	Trip (T1) 1>0	450,0 ms	450,0 ms	0,000 s	406,6 ms	-43,40 ms	+

Assess: + .. Passed x .. Failed o .. Not assessed

State Assessment

	Normal situtation	Pick-up Grp1 (I2=2.1%)	Drop-off Grp1	Normal situation grp2	Pick-up Grp2	Drop-off Grp2
Assess	+	+	+	+	+	+
Tolerance	0,000 s	9,438 s	450,0 ms	0,000 s	120,3 s	450,0 ms
Start (A1)	0	1	0	0	1	0
Trip (T1)	0	1	0	0	1	0

Assess: + .. Passed x .. Failed o .. Not assessed

Test State:

Test passed

---------- Group end:CT 5A ----------

---------- Group end:Motor mode ----------

---------- Group end:Unbalance stage I'2> (46) ----------